

# P-Channel 60-V (D-S) MOSFET

PRODU	ICT SUMMARY		
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)
- 60	0.019 at V <sub>GS</sub> = - 10 V	- 53	38 nC
- 00	0.026 at V <sub>GS</sub> = - 4.5 V	- 42	30 110

# TO-220AB

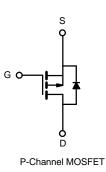
#### FEATURES

- TrenchFET<sup>®</sup> Power MOSFET
- 100 % UIS Tested

#### **APPLICATIONS**

· Load Switch





Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V <sub>DS</sub>	- 60	v
Gate-Source Voltage		V <sub>GS</sub>	± 20	V
	T <sub>C</sub> = 25 °C		- 53 <sup>a</sup>	
Continuous Droin Current (T $= 150$ °C)	T <sub>C</sub> = 70 °C		- 46.8	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	-9.2 <sup>b</sup>	•
	T <sub>A</sub> = 70 °C		- 8.1 <sup>b</sup>	A
Pulsed Drain Current		I <sub>DM</sub>	- 200	
valanche Current Pulse		I <sub>AS</sub>	- 45	
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	101	mJ
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	1	69 <sup>a</sup>	A
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.1 <sup>b</sup>	A
	T <sub>C</sub> = 25 °C		104.2 <sup>a</sup>	
Maximum Power Dissipation	T <sub>C</sub> = 70 °C		66.7 <sup>a</sup>	14/
	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>b</sup>	W
	T <sub>A</sub> = 70 °C		2 <sup>b</sup>	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	33	40	°C/W
Maximum Junction-to-Case	Steady State	R <sub>thJC</sub>	0.98	1.2	0/00

Notes:

a. Based on T<sub>C</sub> = 25 °C.

b. Surface mounted on 1" x 1" FR4 board.

### **VBM2625**

<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C,	unless othe	erwise noted)					
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = -250 \mu A$	- 60			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I <sub>D</sub> = - 250 μA		68		mV/°0	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	iD = - 200 μΛ		- 5.2		mv/ C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 1		- 3	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zene Octo Melle en Decis Oremant		$V_{DS} = -60 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS}$ = - 60 V, $V_{GS}$ = 0 V, $T_{J}$ = 55 °C			- 10	μA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> = - 5 V, V <sub>GS</sub> = - 10 V	- 120			Α	
Drain-Source On-State Resistance <sup>a</sup>		V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 30 A		0.019		0	
	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 20 A		0.026		Ω	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 50 A	20			S	
Dynamic <sup>b</sup>					•	•	
Input Capacitance	C <sub>iss</sub>			3500		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ = - 25 V, $V_{GS}$ = 0 V, f = 1 MHz		390			
Reverse Transfer Capacitance	C <sub>rss</sub>			290			
	Qg	$V_{DS} = -30$ V, $V_{GS} = -10$ V, $I_{D} = -55$ A		76	115	nC	
Total Gate Charge				38	60		
Gate-Source Charge	Q <sub>gs</sub>	$V_{\rm DS}$ = - 30 V, $V_{\rm GS}$ = - 4.5 V, $I_{\rm D}$ = - 55 A		16			
Gate-Drain Charge	Q <sub>gd</sub>			19			
Gate Resistance	Rg	f = 1 MHz		5.2		Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			10	15		
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 2 V, $R_L$ = 2 $\Omega$		7	15	- ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D$ $\cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 $\Omega$		70	110		
Fall Time	t <sub>f</sub>			40	60		
Drain-Source Body Diode Characteristic	s				•		
Continuous Source-Drain Diode Current	ا <sub>S</sub>	T <sub>C</sub> = 25 °C			- 69	٨	
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				- 150	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 30 A		- 1	- 1.5	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			45	68	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			59	120	nC	
Reverse Recovery Fall Time	ta	$I_F = -50 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 \text{ °C}$		29			
Reverse Recovery Rise Time	t <sub>b</sub>			16		ns	

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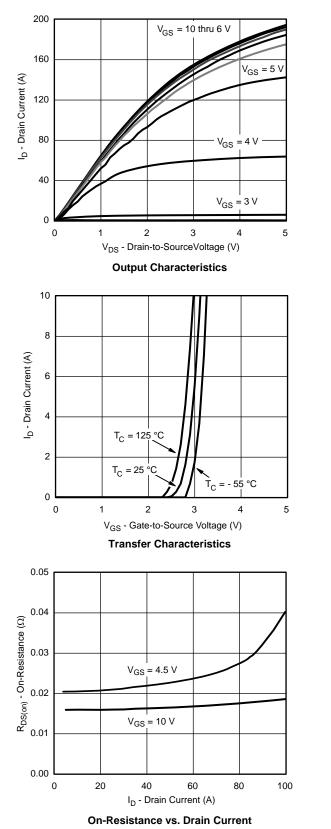
Notes:

a. Pulse test; pulse width  $\leq$  300  $\mu s,$  duty cycle  $\leq$  2 %.

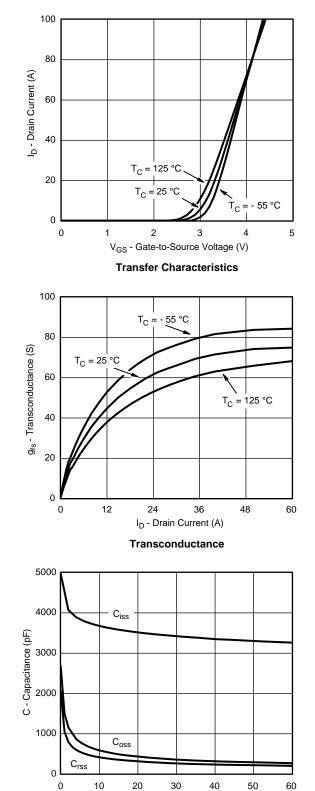
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





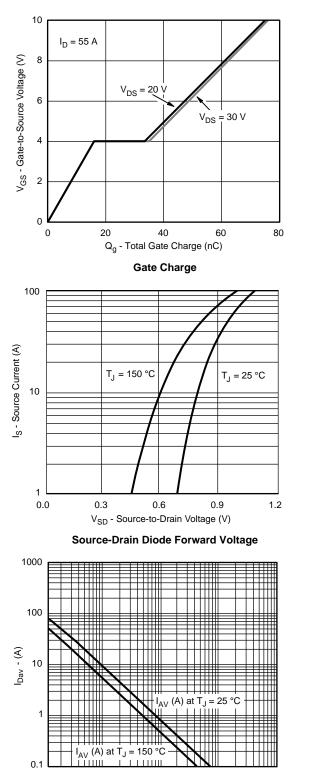
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



 $\rm V_{DS}$  - Drain-to-Source Voltage (V)

Capacitance





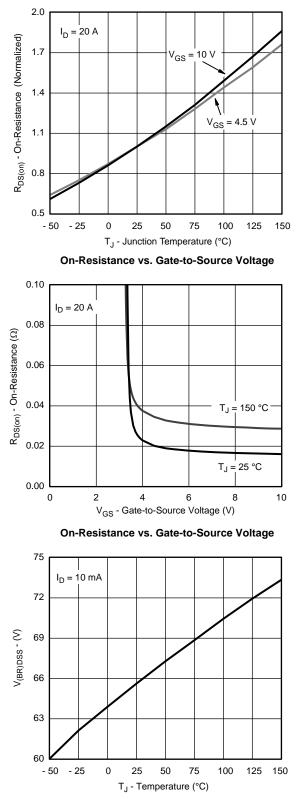
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

 $\label{eq:Tin-s} T_{in} \text{ - } (s)$  Single Pulse Avalanche Current Capability vs. Time

0.01

0.1

1

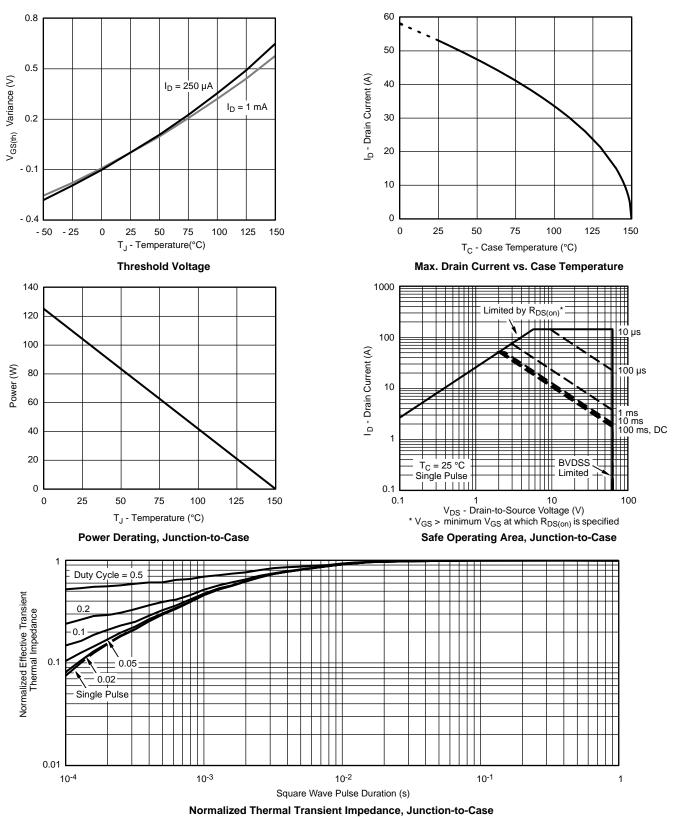


Drain-Source Breakdown Voltage vs. Junction Temperature

0.0001

0.001

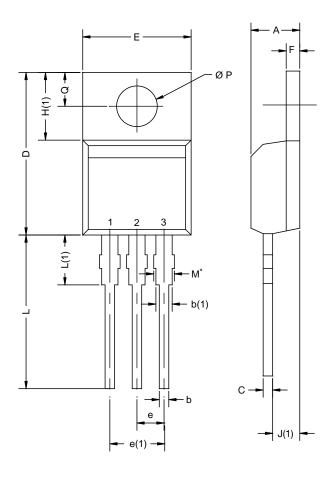




#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



## **TO-220AB**



DIM.	MILLIN	<b>IETERS</b>	INCHES		
	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

#### Notes

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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